


<b>Search Notes</b>  	<b>Application/Control No.</b>  10559857	<b>Applicant(s)/Patent Under Reexamination</b>  FRALEY ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1609

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN Structure	6/12/2007	SL
PALM Inventor (all inventors)	6/13/2007	SL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner